



Increased process yield and uptime



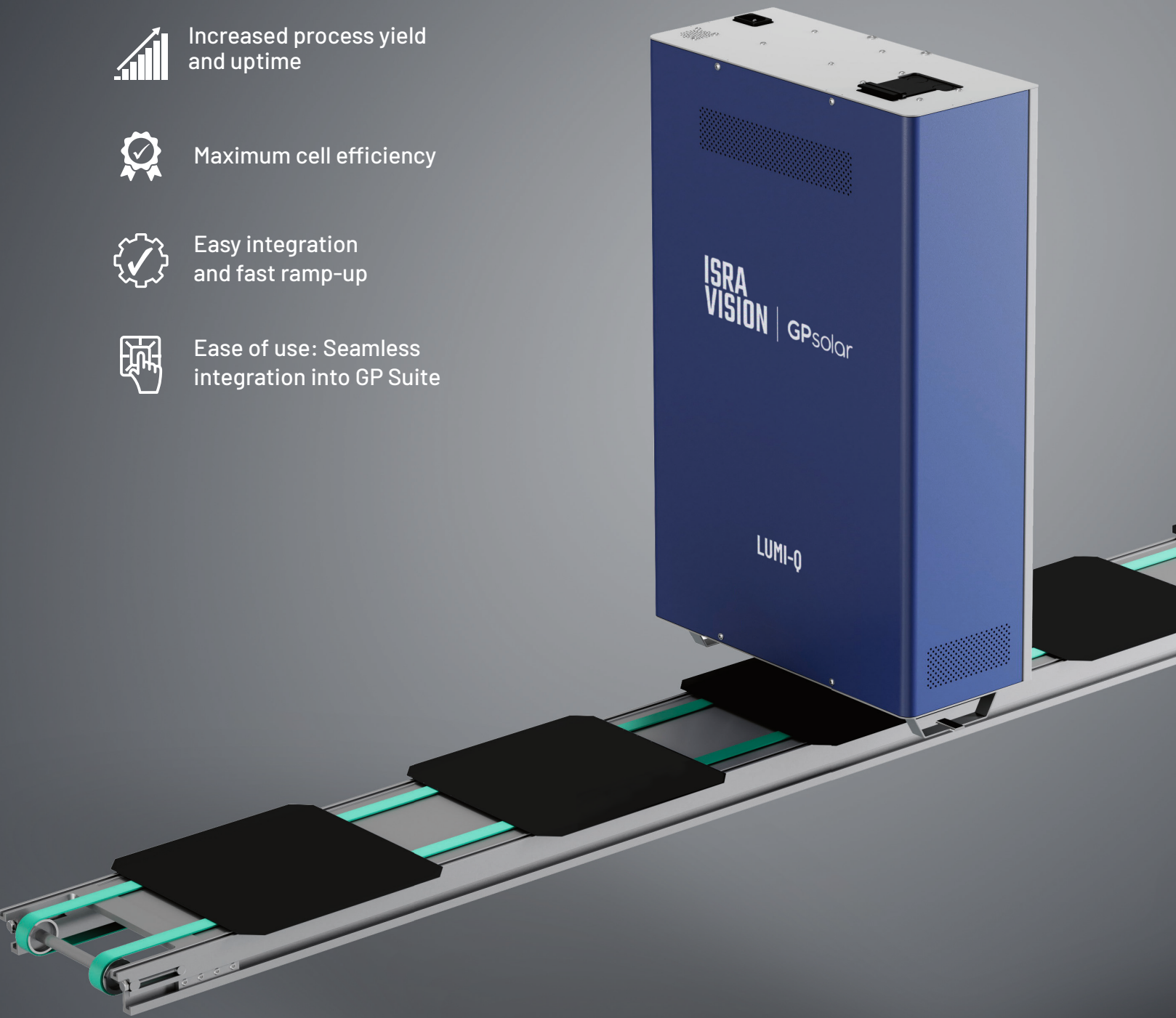
Maximum cell efficiency



Easy integration and fast ramp-up



Ease of use: Seamless integration into GP Suite



## LUMI-Q Coating

Pre- and post-coating  
photoluminescence inspection



## ABOUT LUMI-Q COATING

LUMI-Q Coating is a photoluminescence inspection system designed for pre- and post-coating inspection. It automatically detects all relevant defects that have a negative impact on cell efficiency. With the information generated by LUMI-Q Coating during the inspection, the system provides immediate feedback on the process, which can then be corrected or continued accordingly. Without a laser and therefore without additional safety measures, LUMI-Q Coating delivers reliable results with fast cycle times and high production volumes. Thanks to the unique ISRA VISION GP platform design, LUMI-Q Coating can be integrated into existing systems without any additional footprint and fits seamlessly into the existing GP software suite.

## DEFECTS

**Material defects:** Microcracks, impurities, crystal defects, cell breakage

**Coating defects:** Scratches, stains, passivation defects

- For layers with very high lateral conductivity (e.g. very high doped TCO for HTL/ETL): defects affecting lateral current flow
- Defects caused by shading, e.g. objects such as wafer debris

## PROCESSES

### HJT (xBC)

- i:a-Si deposition
- n:a-Si, p:a-Si, n:μc-Si, p:μc-Si deposition
- TCO coating

### TopCon (xBC)

- Poly-deposition
- AlOx coating
- SiNx coating

### Perovskite

Bottom cell:

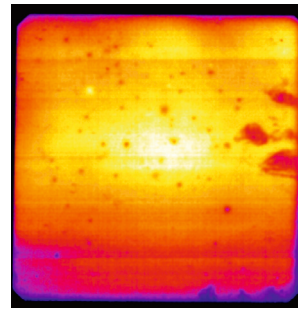
- Poly-deposition
- AlOx coating
- SiNx coating

Top cell:

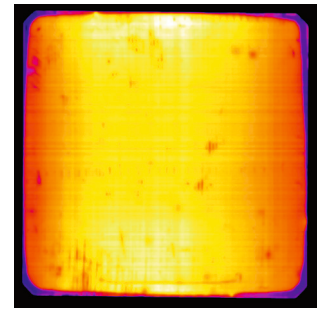
- TCO bottom
- ETL/Absorber/HTL
- TCO top

## KEY FEATURES

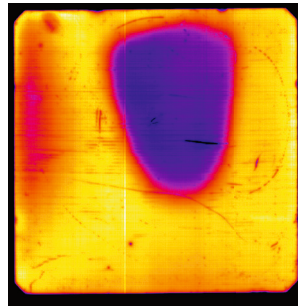
- Laser-free – reduced safety requirements
- Seamless integration into standard handling equipment
- On-the-fly scanning
- Fast measurement speed:  $\geq 1500$  mm/s @ 1k
- Easy integration into GP Software Suite and fab data management (Connected PV 4.0)
  - Central recipe management
  - Central data reporting
  - Interface to MES system



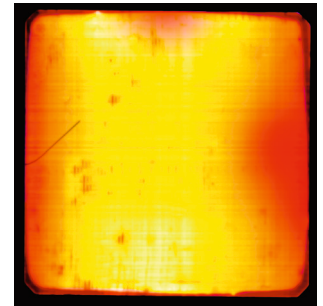
Photoluminescence enables checking the electrical material properties inside the cell.



Edge wrap-around in poly deposition



Passivation issue in FS PECVD



Cracks